

IFW

DOCKET NO.: 4685

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN THE MATTER OF THE APPLICATION FOR PATENT

OF: Shinsuke FUJIWARA et al.

| ART UNIT: 2811

SERIAL NO.: 10/829,306

| CONF. NO.: 5680

FILED: April 20, 2004

| EXAMINER: A. O. ARENA

FOR: SEMICONDUCTOR LIGHT EMITTING DEVICE

COMMISSIONER FOR PATENTS
P.O. BOX 1450
ALEXANDRIA, VA 22313-1450

January 9, 2007

INFORMATION DISCLOSURE STATEMENT WITH CERTIFICATE OF MAILING

Dear Sir:

- 1) Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98 applicants enclose a Third Form PTO-1449, copies of references AG to AS cited thereon, English Abstracts as indicated on Form PTO-1449, and a copy as well as an English translation of a Japanese Office Action issued on October 10, 2006 in a counterpart Japanese application.
- 2) This Information Disclosure Statement is being filed before the issuance of a Final Office Action (after filing an RCE) or Notice of Allowance and includes a statement under 37 CFR 1.97(e) (see next paragraph). Thus, in accordance with 37 CFR 1.97(c)(1), no fee is due.

- 3) The undersigned attorney hereby certifies that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement.
- 4) References AE and AF are in English. References AG to AS are accompanied by English Abstracts. Reference AP corresponds to AE, and AS corresponds to AF, from which the relevance can be determined in English. Therefore no further discussion of the references is necessary.
- 5) Moreover, the enclosed English translation of the Japanese Office Action shows why the Japanese Examiner found references AG to AS to be relevant to the counterpart Japanese patent application. The Japanese Examiner's statements are not ratified as accurate or adopted by applicant, but they are submitted for the US Examiner's consideration as to the possible relevance of the references. The two additional references (JP09-293937 and JP07-321409) cited in the Japanese Office Action have already been submitted in our Information Disclosure Statement dated November 7, 2005.
- 6) The Examiner is requested to consider all references of record, return an initialed copy of the enclosed Form PTO-1449 and ensure that all references of record are printed on any patent issuing from this application.

- 7) A Response to the Office Action of August 31, 2006 will be filed in due course.



Respectfully submitted,
Shinsuke FUJIWARA et al.
Applicant

WFF:ks/4685
Enclosures:
postcard,
Third Form PTO-1449,
13 references,
13 English abstracts,
copy and English translation
of Japanese Office Action

By Walter F. Fasse
Walter F. Fasse
Patent Attorney
Reg. No.: 36132
Tel. No.: 207-862-4671
Fax. No.: 207-862-4681
P.O. Box 726
Hampden, ME 04444-0726

CERTIFICATE OF MAILING:

I hereby certify that this correspondence with all indicated enclosures is being deposited with the U. S. Postal Service with sufficient postage as first-class mail, in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date indicated below.

Karin Smith - January 9, 2007

Name: Karin Smith - Date: January 9, 2007

Sheet 1 of 1
**THIRD IDS LIST OF REFERENCES
 CITED BY APPLICANT**
 (FORM PTO-1449)
 DATED: January 9, 2007

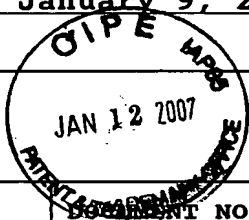
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Inventor(s): Shinsuke FUJIWARA et al.

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Art Unit:
 2811



U. S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	Cl.	Sub- Cl.	Fil. Date
	AE	6,177,690	01/2001	Noguchi et al.	-	-	-
	AF	6,265,734	07/2001	Fischer et al.	-	-	-

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	Cl.	Sub- Cl.	English
	AG	03-071679	03/1991	Japan	-	-	Abstract
	AH	03-270186	12/1991	Japan	-	-	Abstract
	AI	05-243674	09/1993	Japan	-	-	Abstract
	AJ	06-061580	03/1994	Japan	-	-	Abstract
	AK	07-193328	07/1995	Japan	-	-	Abstract
	AL	07-321375	12/1995	Japan	-	-	Abstract
	AM	09-083086	03/1997	Japan	-	-	Abstract
	AN	09-331114	12/1997	Japan	-	-	Abstract
	AO	11-145565	05/1999	Japan	-	-	Abstract
	AP	11-150334	06/1999	Japan	-	-	Abstract, = AE
	AQ	11-289108	10/1999	Japan	-	-	Abstract
	AR	62-122190	06/1987	Japan	-	-	Abstract
	AS	2000-500288	01/2000	Japan	-	-	Abstr., =AF

OTHER DOCUMENTS

EXAMINER'S SIGNATURE

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.